

Jc979 U.S. PTO  
10/024930

Jc1024



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# U.S. UTILITY Patent Application

PATENT NUMBER and  
ISSUE DATE

APPL NUM 13024930	FILING DATE 12/19/2001	CLASS 250	SUBCLASS 2878	GAU 2878	EXAMINER [Signature]
<b>**APPLICANTS:</b> Madsen Ian; Scarlett Nicola; Manias Constantine; Retallack David; Schneider Karl;					
<b>**CONTINUING DATA VERIFIED:</b> THIS APPLICATION IS A CON OF PCT/AU00/00697 06/21/2000					
<b>** FOREIGN APPLICATIONS VERIFIED:</b> AUSTRALIA PQ1094 06/21/1999					
PG-PUB		DO NOT PUBLISH <input type="checkbox"/>		RESCIND <input type="checkbox"/>	
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no Verified and Acknowledged Examiners's initials				ATTORNEY DOCKET NO POF 3.9-050 CONT	
TITLE : Method and apparatus for X-ray diffraction analyses					

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<b>NOTICE OF ALLOWANCE MAILED</b>		<b>CLAIMS ALLOWED</b>	
<b>ISSUE FEE</b> Amount Due      Date Paid		Assistant Examiner	
		Primary Examiner	
<input type="checkbox"/> <b>TERMINAL</b>		<b>DRAWING</b> Sheets Drwg.      Figs.Drwg.      Print Fig.	
		Application Examiner	
<b>PREPARED FOR ISSUE</b>			

U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)